

**Search Notes**

Application/Control No.

10/676,754

Examiner

Patricia Leith

Applicant(s)/Patent under  
Reexamination

HON ET AL.

Art Unit

1655

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST: JPO,EPO,DERWENT,USPATFULL,U SPGPUBS,OCRBACKFILE	12/5/2005	PL
Inventor name search PALM/EAST	12/5/2005	PL